

Phase-out/Discontinued **μ PA1556**

N-CHANNEL POWER MOS FET ARRAY SWITCHING TYPE

DESCRIPTION

The μ PA1556 is N-channel Power MOS FET Array that built in 4 circuits designed for solenoid, motor and lamp driver.

FEATURES

- 4 V driving is possible
- Large Current and Low On-state Resistance
 $I_D(\text{pulse}) = \pm 20 \text{ A}$
 $R_{DS(on)} = 0.20 \Omega \text{ TYP. } (V_{GS} = 10 \text{ V})$
 $R_{DS(on)} = 0.25 \Omega \text{ TYP. } (V_{GS} = 4 \text{ V})$
- 2.54 mm Pitch (0.1 inch)

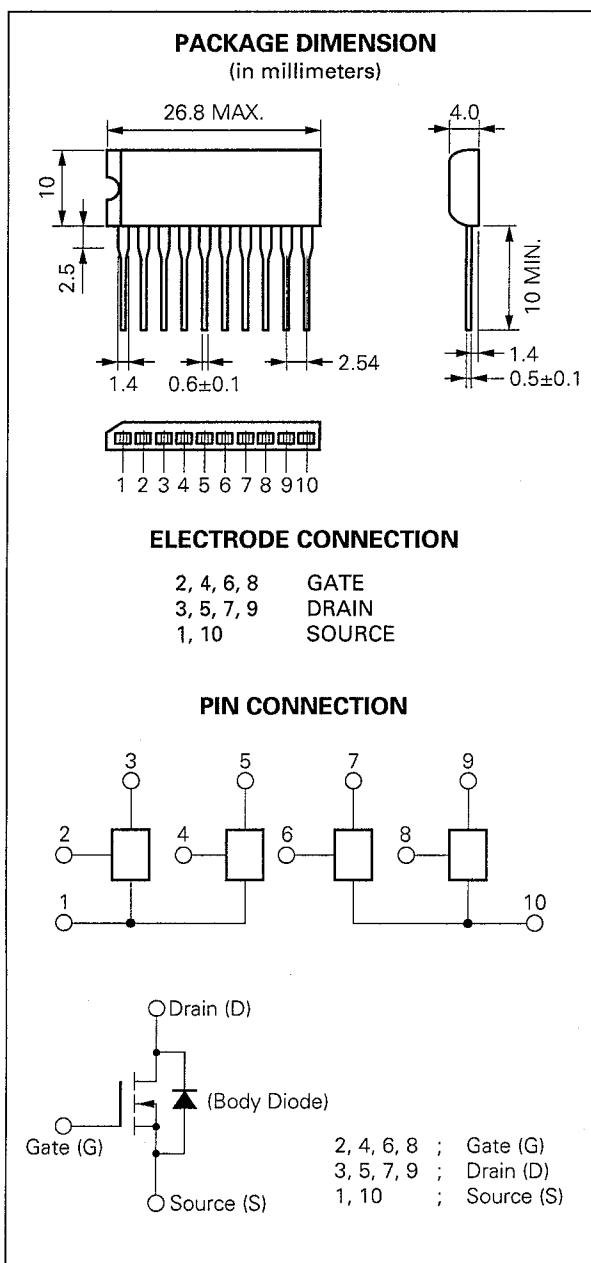
ORDERING INFORMATION

Part Number	Package	Quality Grade
μ PA1556H	10 Pin SIP	Standard

Please refer to "Quality grade on NEC Semiconductor Devices" (Document number IEI-1209) published by NEC Corporation to know the specification of quality grade on the devices and its recommended applications.

ABSOLUTE MAXIMUM RATINGS ($T_a = 25^\circ\text{C}$)

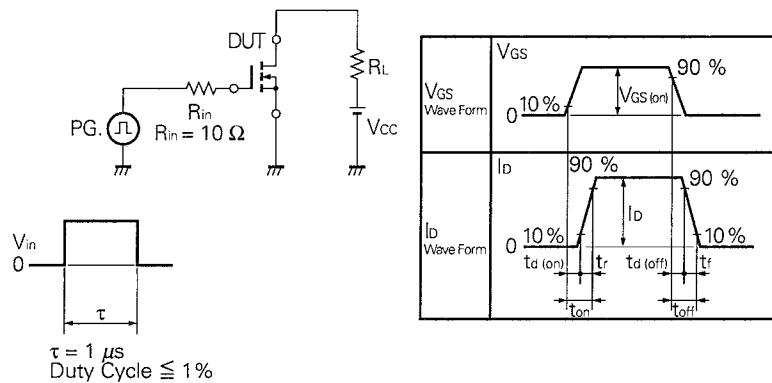
Drain to Source Voltage	V_{DSS}	100	V
Gate to Source Voltage	V_{GSS}	± 20	V
Drain Current (DC)	$I_D(\text{DC})$	± 5.0	A/unit
Drain Current (pulse)	$I_D(\text{pulse})$	± 20	A/unit
Total Power Dissipation (4 circuits)			
$<T_c = 25^\circ\text{C}>$	P_{T1}	28	W
Total Power Dissipation (4 circuits)			
$<T_a = 25^\circ\text{C}>$	P_{T2}	3.5	W
Storage Temperature	T_{stg}	-55 to +150	$^\circ\text{C}$
Junction Temperature	T_j	150	$^\circ\text{C}$
PW $\leq 300 \mu\text{s}$, Duty Cycle $\leq 10\%$			

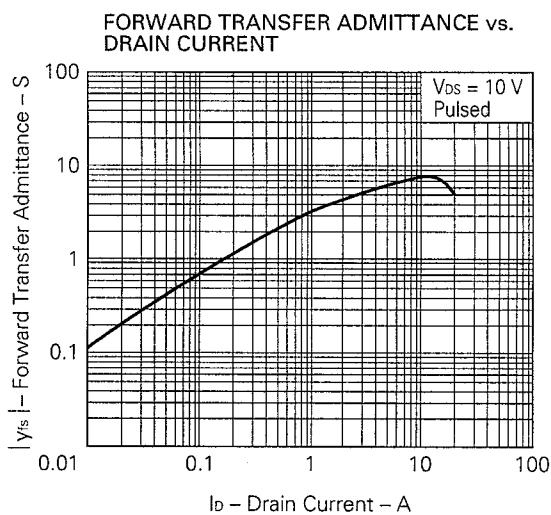
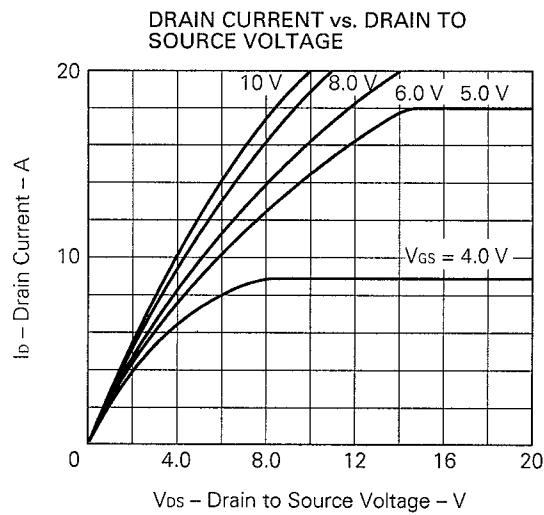
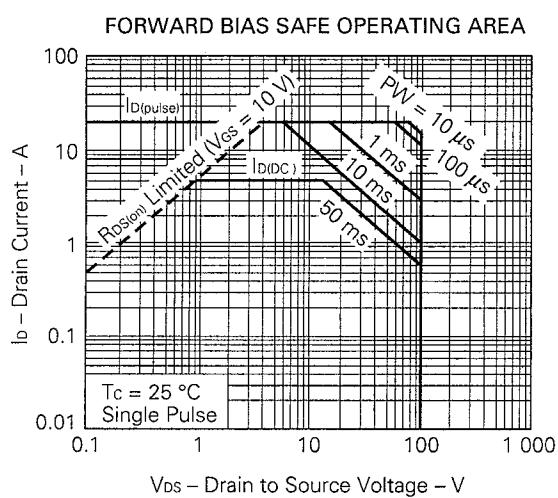
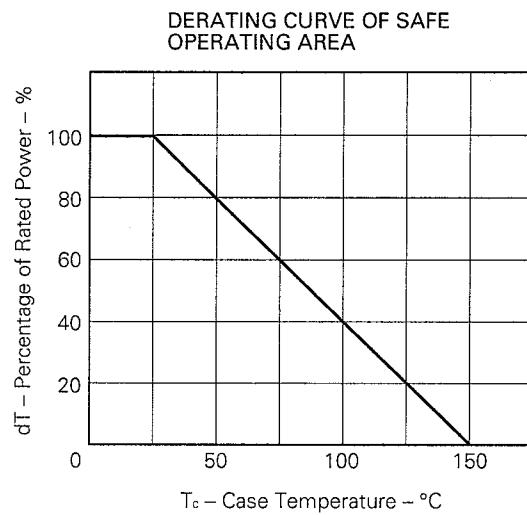
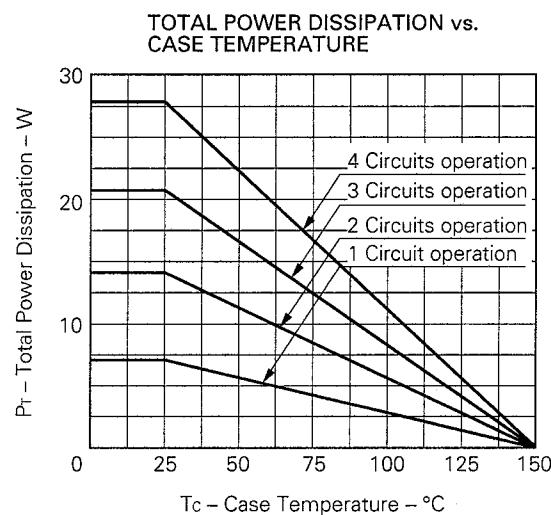
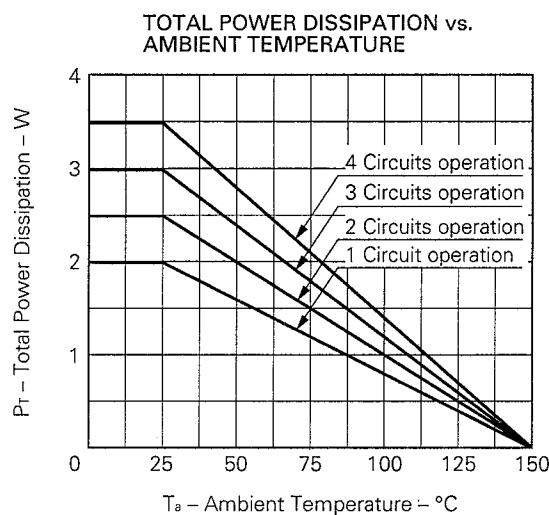


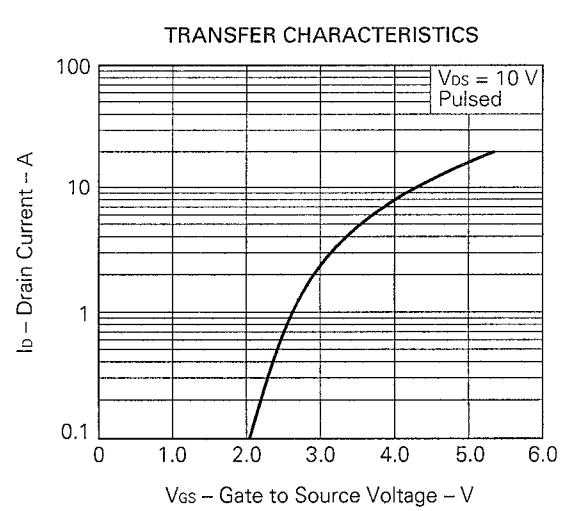
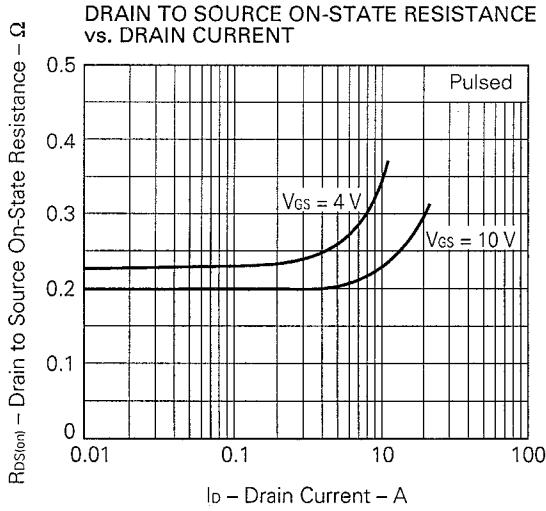
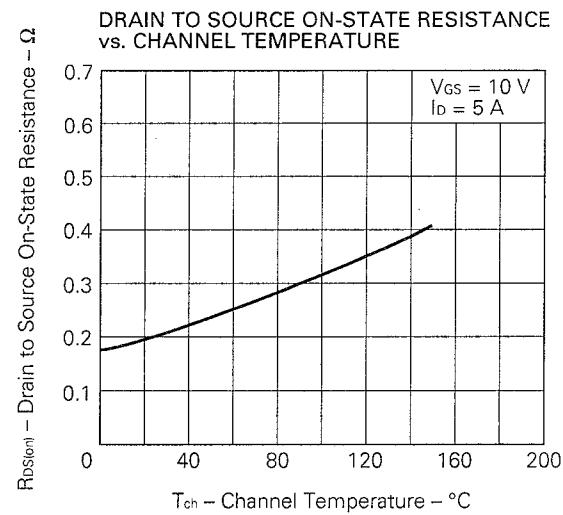
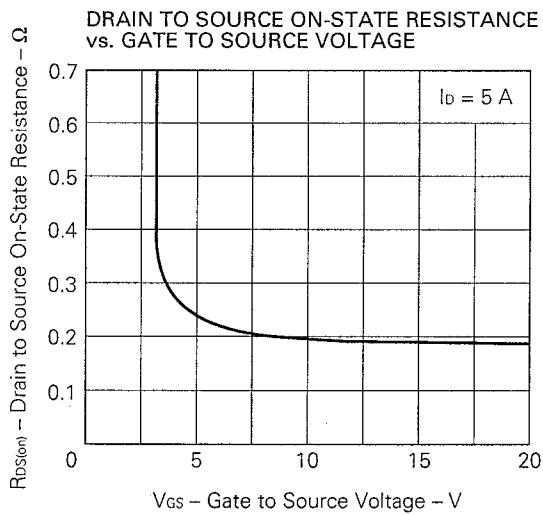
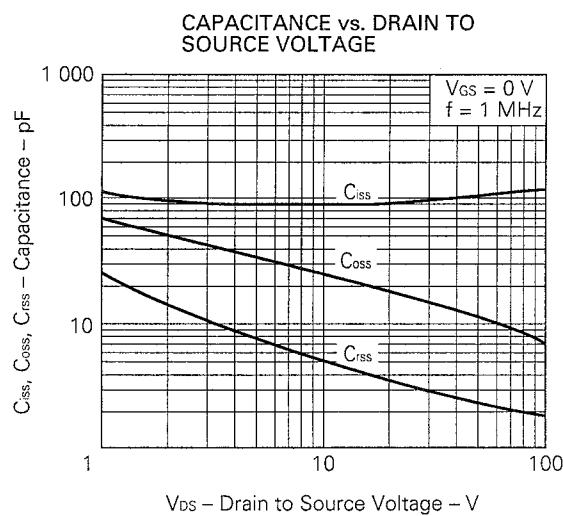
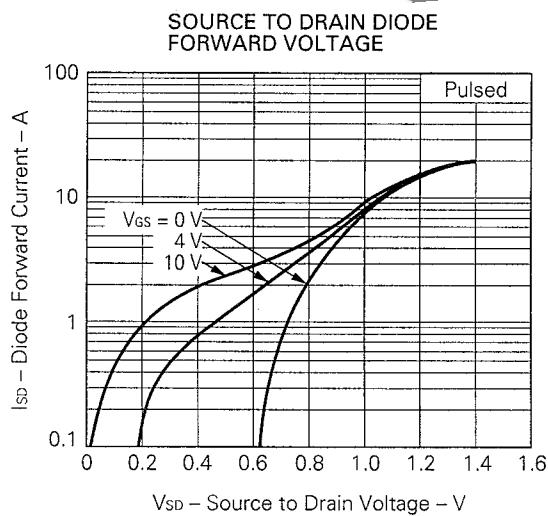
Phase-out/Discontinued

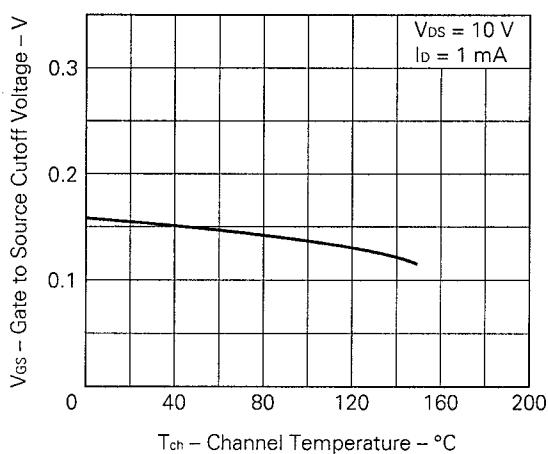
ELECTRICAL CHARACTERISTICS ($T_a = 25^\circ\text{C}$)

CHARACTERISTICS	SYMBOL	MIN.	TYP.	MAX.	UNIT	TEST CONDITIONS
Drain Leakage Current	I_{DSS}			10	μA	$V_{DS} = 100\text{ V}, V_{GS} = 0$
Gate to Source Leakage Current	I_{GSS}			± 100	nA	$V_{GS} = \pm 20\text{ V}, V_{DS} = 0$
Gate to Source Cutoff Voltage	$V_{GS(\text{off})}$	1.0		2.5	V	$V_{DS} = 10\text{ V}, I_D = 1\text{ mA}$
Forward Transfer Admittance	$ Y_{fs} $	4.0			S	$V_{DS} = 10\text{ V}, I_D = 3\text{ A}$
Drain to Source On-state Resistance	$R_{DS(on)1}$		0.2	0.45	Ω	$V_{GS} = 10\text{ V}, I_D = 5\text{ A}$
Drain to Source On-state Resistance	$R_{DS(on)2}$		0.25	0.5	Ω	$V_{GS} = 4\text{ V}, I_D = 5\text{ A}$
Input Capacitance	C_{iss}		900		pF	$V_{DS} = 10\text{ V}$ $V_{GS} = 0$ $f = 1.0\text{ MHz}$
Output Capacitance	C_{oss}		250		pF	
Reverse Transfer Capacitance	C_{rss}		50		pF	
Turn-On Delay Time	$t_{d(on)}$		10		ns	$I_D = 3\text{ A}$ $V_{GS} = 10\text{ V}$ $V_{CC} = 50\text{ V}$ $R_L = 17\text{ }\Omega$ $R_{in} = 10\text{ }\Omega$ See Fig. 1
Rise Time	t_r		40		ns	
Turn-Off Delay Time	$t_{d(off)}$		110		ns	
Fall Time	t_f		30		ns	

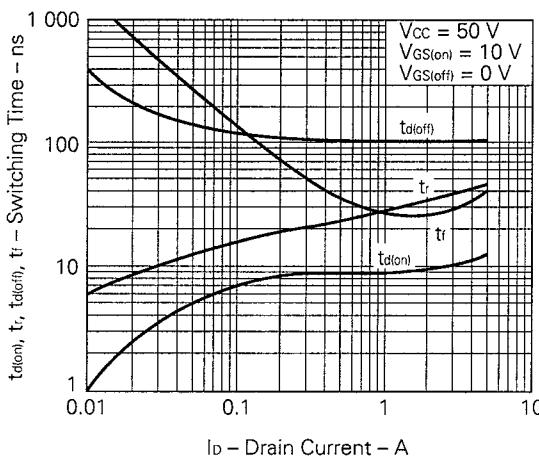
Fig. 1 Switching Time Test Circuit


Phase-out/Discontinued**TYPICAL CHARACTERISTICS ($T_a = 25^\circ\text{C}$)**

Phase-out/Discontinued

Phase-out/DiscontinuedGATE TO SOURCE CUTOFF VOLTAGE
vs. CHANNEL TEMPERATURE

SWITCHING TIME vs. DRAIN CURRENT

**Reference**

Application note name	No.
Quality control of NEC semiconductors devices.	TEI-1202
Quality control guide of semiconductors devices.	MEI-1202
Assembly manual of semiconductors devices.	IEI-1207
Safe operating area of Power MOS FET	TEA-1034
Application circuit using Power MOS FET	TEA-1035